

November 2013

FQPF13N06L

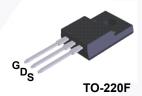
N-Channel QFET[®] MOSFET 60 V, 10 A, 110 m Ω

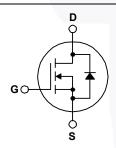
Description

This N-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

Features

- 10 A, 60 V, $R_{DS(on)}$ = 110 m Ω (Max.) @ V_{GS} = 10 V, I_D = 5 A
- Low Gate Charge (Typ. 4.8 nC)
- Low Crss (Typ. 17 pF)
- · 100% Avalanche Tested
- · 175°C Maximum Junction Temperature Rating





Absolute Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol	Parameter		FQPF13N06L	Unit
V_{DSS}	Drain-Source Voltage		60	V
I _D	Drain Current - Continuous (T _C = 25°	C)	10	Α
	- Continuous (T _C = 100)°C)	7.1	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	40	Α
V _{GSS}	Gate-Source Voltage		± 20	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	90	mJ
I _{AR}	Avalanche Current	(Note 1)	10	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	2.4	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	7.0	V/ns
P_{D}	Power Dissipation (T _C = 25°C)		24	W
	- Derate above 25°C		0.16	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +175	°C
T _L	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	FQPF13N06L	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	6.20	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	62.5	°C/W

Package Marking and Ordering Information

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FQPF13N06L	FQPF13N06L	TO-220F	Tube	N/A	N/A	50 units

Floctrical Characteristics

Parameter	Test Conditions	Min	Тур	Max	Uni
aracteristics					
Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA	60			V
Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		0.05		V/°C
Zana Oata Valtana Brain Ourrant	V _{DS} = 60 V, V _{GS} = 0 V			1	μΑ
Zero Gate Voltage Drain Current	V _{DS} = 48 V, T _C = 150°C			10	μА
Gate-Body Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
Gate-Body Leakage Current, Reverse	V _{GS} = -20 V, V _{DS} = 0 V			-100	nA
aracteristics					
Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1.0		2.5	V
Static Drain-Source	V _{GS} = 10 V, I _D = 5 A		0.088	0.11	
On-Resistance	$V_{GS} = 5 \text{ V}, I_D = 5 \text{ A}$		0.110	0.14	Ω
Forward Transconductance	V _{DS} = 25 V, I _D = 5 A		5.5		S
ic Characteristics					
Input Capacitance	V _{DS} = 25 V, V _{GS} = 0 V, f = 1.0 MHz		270	350	pF
Output Capacitance			95	125	pF
Reverse Transfer Capacitance			17	23	pF
				20	P .
ing Characteristics	,			20	
ing Characteristics Turn-On Delay Time)		8	25	ns
	$V_{DD} = 30 \text{ V}, I_{D} = 6.8 \text{ A},$		8 90		ns
Turn-On Delay Time	$V_{DD} = 30 \text{ V}, I_{D} = 6.8 \text{ A},$ $R_{G} = 25 \Omega$			25	ns
Turn-On Delay Time Turn-On Rise Time	22		90	25 190	ns ns
Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time	R_G = 25 Ω (Note 4)		90	25 190 50	ns ns ns
Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time	R_G = 25 Ω (Note 4) V_{DS} = 48 V, I_D = 13.6 A,	 	90 20 40	25 190 50 90	ns ns ns
Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge	R_G = 25 Ω (Note 4)	 /	90 20 40 4.8	25 190 50 90	ns ns ns ns
Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge	R_G = 25 Ω (Note 4) V_{DS} = 48 V, I_D = 13.6 A, V_{GS} = 5 V (Note 4)		90 20 40 4.8 1.6	25 190 50 90 6.4 	ns ns ns ns
Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge	$R_G = 25 \Omega \end{tabular}$ (Note 4) $V_{DS} = 48 \text{V}, I_D = 13.6 \text{A}, \end{tabular}$ (Note 4) $V_{GS} = 5 \text{V} \end{tabular}$ (Note 4)	 	90 20 40 4.8 1.6 2.7	25 190 50 90 6.4 	ns ns ns ns nC
Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge Source Diode Characteristics and Maximum Continuous Drain-Source Diode	R_G = 25 Ω (Note 4) V_{DS} = 48 V, I_D = 13.6 A, V_{GS} = 5 V (Note 4) V_{DS} = 48 V, V_{DS} = 10 Maximum Ratings ode Forward Current		90 20 40 4.8 1.6 2.7	25 190 50 90 6.4 	ns ns ns nc nC
Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge Source Diode Characteristics and Maximum Continuous Drain-Source Diode Fall Time	$R_G = 25 \Omega$ (Note 4) $V_{DS} = 48 \text{ V}, I_D = 13.6 \text{ A}, V_{GS} = 5 \text{ V}$ (Note 4) and Maximum Ratings ode Forward Current Forward Current		90 20 40 4.8 1.6 2.7	25 190 50 90 6.4 	ns ns ns nc nC
Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge Gate-Drain Charge Source Diode Characteristics and Maximum Continuous Drain-Source Diode	R_G = 25 Ω (Note 4) V_{DS} = 48 V, I_D = 13.6 A, V_{GS} = 5 V (Note 4) V_{DS} = 48 V, V_{DS} = 10 Maximum Ratings ode Forward Current		90 20 40 4.8 1.6 2.7	25 190 50 90 6.4 	ns ns ns nc nC
	Drain-Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate-Body Leakage Current, Forward Gate-Body Leakage Current, Reverse Bracteristics Gate Threshold Voltage Static Drain-Source On-Resistance Forward Transconductance ic Characteristics Input Capacitance Output Capacitance	Drain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}$, $I_D = 250 \text{ μA}$ Breakdown Voltage Temperature Coefficient $I_D = 250 \text{ μA}$, Referenced to 25°C Zero Gate Voltage Drain Current $V_{DS} = 60 \text{ V}$, $V_{GS} = 0 \text{ V}$ Gate-Body Leakage Current, Forward $V_{GS} = 20 \text{ V}$, $V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -20 \text{ V}$, $V_{DS} = 0 \text{ V}$ Aracteristics $V_{DS} = V_{GS}$, $I_D = 250 \text{ μA}$ Gate Threshold Voltage $V_{DS} = V_{GS}$, $I_D = 250 \text{ μA}$ Static Drain-Source $V_{GS} = 10 \text{ V}$, $V_{DS} = 5 \text{ A}$ On-Resistance $V_{DS} = 25 \text{ V}$, $V_{DS} = 5 \text{ A}$ Forward Transconductance $V_{DS} = 25 \text{ V}$, $V_{CS} = 0 \text{ V}$ ic Characteristics $V_{DS} = 25 \text{ V}$, $V_{CS} = 0 \text{ V}$ Input Capacitance $V_{DS} = 25 \text{ V}$, $V_{CS} = 0 \text{ V}$ Output Capacitance $V_{DS} = 25 \text{ V}$, $V_{CS} = 0 \text{ V}$	Drain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}$, $I_D = 250 \text{ μA}$ 60Breakdown Voltage Temperature Coefficient $I_D = 250 \text{ μA}$, Referenced to 25°C Zero Gate Voltage Drain Current $V_{DS} = 60 \text{ V}$, $V_{GS} = 0 \text{ V}$ Gate-Body Leakage Current, Forward $V_{GS} = 20 \text{ V}$, $V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -20 \text{ V}$, $V_{DS} = 0 \text{ V}$ aracteristicsGate Threshold Voltage $V_{DS} = V_{GS}$, $I_D = 250 \text{ μA}$ 1.0Static Drain-Source $V_{GS} = 10 \text{ V}$, $I_D = 5 \text{ A}$ On-Resistance $V_{GS} = 5 \text{ V}$, $I_D = 5 \text{ A}$ Forward Transconductance $V_{DS} = 25 \text{ V}$, $V_{DS} = 0 \text{ V}$, $V_{DS} = 0 \text{ V}$ ic Characteristics $V_{DS} = 25 \text{ V}$, $V_{GS} = 0 \text{ V}$, $V_{DS} = 0 \text{ V}$ Output Capacitance $V_{DS} = 25 \text{ V}$, $V_{GS} = 0 \text{ V}$, $V_{DS} = 0 \text{ V}$ Output Capacitance $V_{DS} = 25 \text{ V}$, $V_{GS} = 0 \text{ V}$, $V_{DS} = 0 \text{ V}$	Drain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}, I_D = 250 \text{ μA}$ 60 Breakdown Voltage Temperature Coefficient $I_D = 250 \text{ μA}, \text{ Referenced to } 25^{\circ}\text{C}$ 0.05 Zero Gate Voltage Drain Current $V_{DS} = 60 \text{ V}, V_{GS} = 0 \text{ V}$ Gate-Body Leakage Current, Forward $V_{GS} = 20 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{DS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{DS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Bod	Drain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}$, $I_D = 250 \text{ μA}$ 60 Breakdown Voltage Temperature Coefficient $I_D = 250 \text{ μA}$, Referenced to 25°C 0.05 Zero Gate Voltage Drain Current $V_{DS} = 60 \text{ V}$, $V_{GS} = 0 \text{ V}$ 1 Gate-Body Leakage Current, Forward $V_{GS} = 20 \text{ V}$, $V_{DS} = 0 \text{ V}$ 100 Gate-Body Leakage Current, Reverse $V_{GS} = -20 \text{ V}$, $V_{DS} = 0 \text{ V}$ -100 Aracteristics Gate Threshold Voltage $V_{DS} = V_{GS}$, $I_D = 250 \text{ μA}$ 1.0 2.5 Static Drain-Source $V_{GS} = 10 \text{ V}$, $I_D = 5 \text{ A}$ 0.088 0.11 On-Resistance $V_{GS} = 5 \text{ V}$, $I_D = 5 \text{ A}$ 0.110 0.14 Forward Transconductance $V_{DS} = 25 \text{ V}$, $V_{DS} = 0 \text{ V}$ 5.5 ic Characteristics Input Capacitance $V_{DS} = 25 \text{ V}$, $V_{GS} = 0 \text{ V}$, $V_{DS} = 0 \text{ V}$ 270 350 95 125

- **Notes:** 1. Repetitive Rating: Pulse width limited by maximum junction temperature. 2. L = 1.05 mH, I_{AS} = 10 A, V_{DD} = 25 V, R_{G} = 25 Ω , starting T_{J} = 25°C. 3. $I_{SD} \le 13.6$ A, di/dt ≤ 300 A/ μ s, $V_{DD} \le BV_{DSS}$, starting T_{J} = 25°C. 4. Essentially independent of operating temperature.

Typical Characteristics

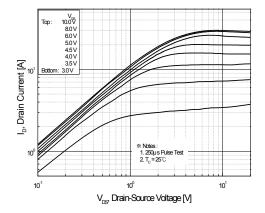


Figure 1. On-Region Characteristics

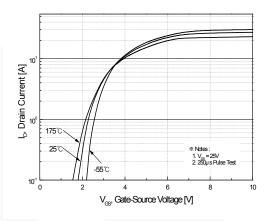


Figure 2. Transfer Characteristics

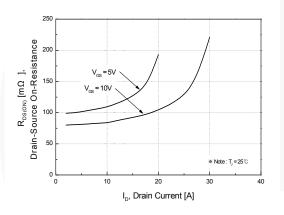


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

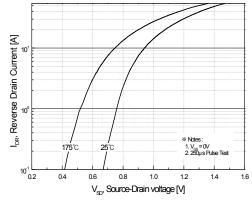


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

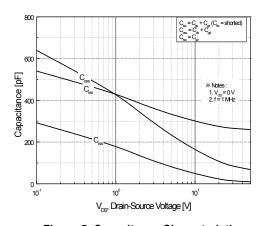


Figure 5. Capacitance Characteristics

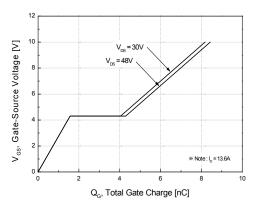


Figure 6. Gate Charge Characteristics

Typical Characteristics (continued)

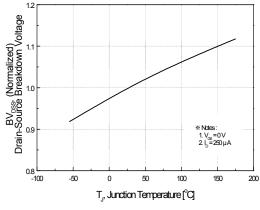


Figure 7. Breakdown Voltage Variation vs. Temperature

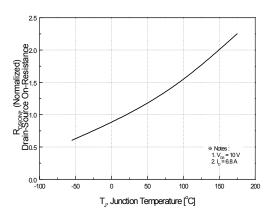


Figure 8. On-Resistance Variation vs. Temperature

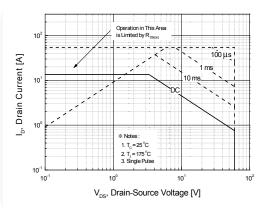


Figure 9. Maximum Safe Operating Area

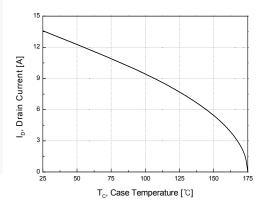


Figure 10. Maximum Drain Current vs. Case Temperature

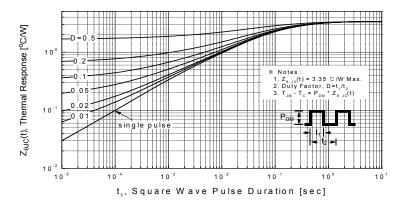


Figure 11. Transient Thermal Response Curve

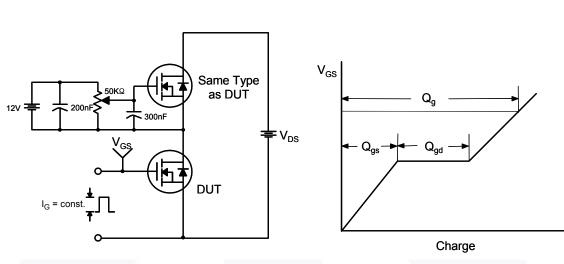


Figure 12. Gate Charge Test Circuit & Waveform

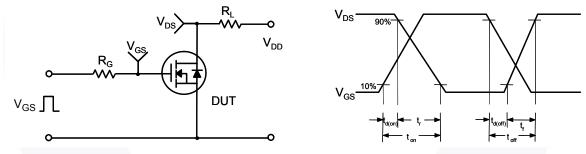


Figure 13. Resistive Switching Test Circuit & Waveforms

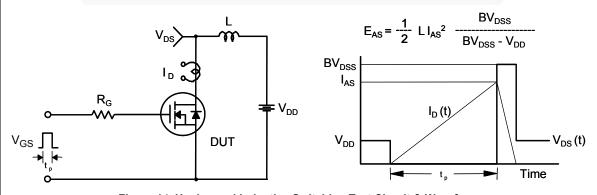
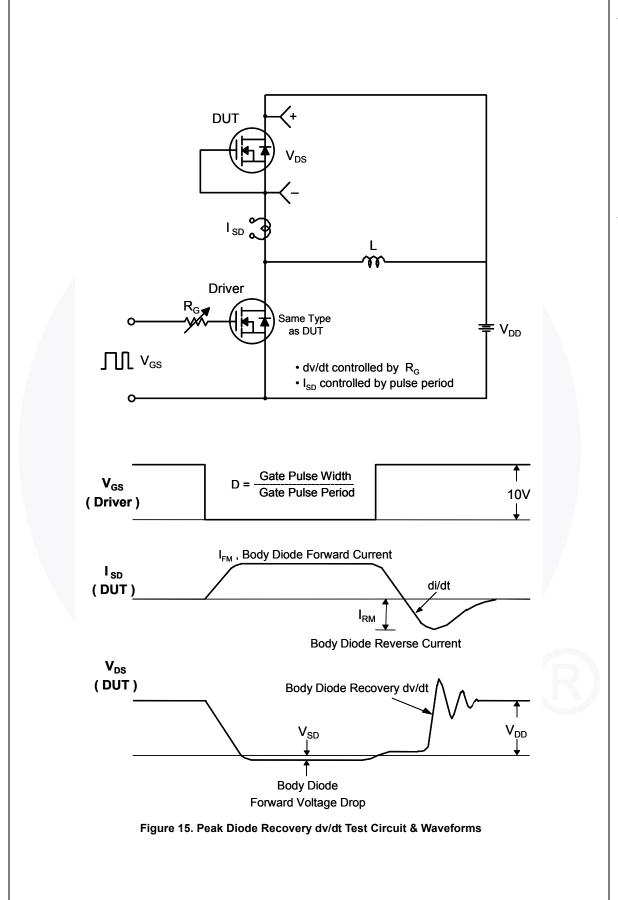


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms



Mechanical Dimensions

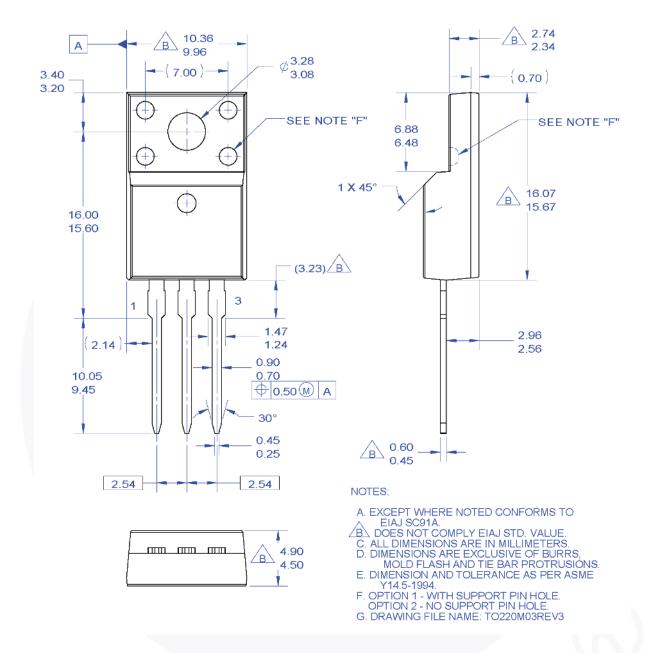


Figure 16. TO220, Molded, 3-Lead, Full Pack, EIAJ SC91, Straight Lead

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